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1. INTRODUCTORY DESCRIPTION

- A. This procedure establishes the methods for testing a
- B. Environmental ranges: 70 +/- 10 Deg. F. with 20-75% R.H.
- C. Unit warm-up/stabilization period requirement: None
- D. Personnel using this procedure are expected to have a high degree of confidence and expertise in related testing and calibration procedures.
- E. Procedures not explained here are considered to be understood as common practice.

2. TEST EQUIPMENT VERIFICATION

- A. Verify the accuracy of the standard(s) used in the repair/calibration process by evidence of recent calibration labeling affixed to the test equipment.
- B. All measurement standards used in this procedure shall be traceable to the NATIONAL INSTITUTE of STANDARDS and TECHNOLOGY (N.I.S.T.) and shall have the accuracy, stability, range and resolution required for the intended use.
- C. Unless otherwise specified, the collective uncertainty of the Measurement Standard(s) shall not exceed twenty five percent of the acceptable tolerance for each characteristic being calibrated.
- D. All deviations shall be documented.

3. EQUIPMENT CLEANING

A. All equipment clean will be performed as instructed in the GE Renewal Services SOP Sec. 14.0

4. EQUIPMENT INSPECTION

- A. The following criteria should be used as a guideline or basis for the inspection process of the this unit:
 - 1. Wires broken or cracked.
 - 2. Terminal strips / connectors broken or cracked.
 - 3. Loose wires.
 - 4. Components visually damaged.
 - 5. Capacitors leaking.
 - 6. Solder joint, cold or otherwise inadequate.
 - 7. Circuit board discolored or burned.
 - 8. Printed wire runs burned or damaged.

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5. <u>REVISION HISTORY</u>

Revision	Date	Reason for Revision
A	12-10-9	Initial Procedure – After Verification
В		
C		
D		
${f E}$		
\mathbf{F}		
G		
H		
I		
J		
K		

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6. REFERENCE DOCUMENTATION

• Reference: GEK

• Factory Procedure #

7. THEORY OF OPERATION

• Reference: GEK

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8. TEST EQUIPMENT TO BE USED

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9. FINAL TEST AND OPERATION PROCESS

- COMMUNICATION TEST (ARCNET & DLAN)
- Double click on icon IOS.
- The IOS menu will appear on screen and Core/Card Test & Load will be highlighted.
- Arrow down to **Down Load & Utilities**.
- Turn switch box to unit to be tested
- Press ENTER
- DS200 SERIES IOS/IEI SERIAL LINK UTILITY will appear on screen followed by selections
- Select Local IOS/IEI ←= File
- Press ENTER
- Download EE Files to IOS Local will appear under DS200 SERIES IOS/IEI LINK
 UTILITY followed by a selection screen.

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- •
- Install card into IOS1/GENIUS.
- Set all jumpers to default position.
- On drive change **EE 706** to 9 for **Arcnet**
- On drive change **EE 706** to 8 for **Dlan**
- Arrow down to specific test you wish to run. Note: you must run both DLAN and ARCNET test.
- Select ARCNET.H09 or DLAN.H09
- Press **ENTER**.
- Scrolling data will appear on PC screen and IOS will reset after download is complete.
- Verify that **ARCNET** or **DLAN** appears in lower right display.
- Verify that **LED** (1) is flashing and **DI01 OK** in lower left-hand display.
- Press **RESET** on drive and verify no fault occur after 80 sec.
- Press and hold **JOG/1** on IOS and verify that contactor on drive picks up and **500 RPM** is displayed on IOS.
- Press RUN on keypad of drive, verify that contactor on drive picks up and 1000 RPM is displayed on IOS.
- Press **STOP** on drive keypad.
- Remove customer firmware and test with Chip Writer
- Install firmware version **DS200DMCBF1BXX** into DMCB
- Remove customer card and re-install test card into IOS1/GENIUS.
- Re-install tested customer firmware into DMCB.
- Install customer card in IOS2/GENIUS. Verify all connection and that a Genius card is installed.
- Verify that IOS1/GENIUS & IOS2/GENIUS are powered up. Note: IOS2/GENIUS will power up with fault 144.

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- Select IOS2/GENIUS on switch box.
- Select CARD/CORE Test & Load from IOS menu.
- I/O TEST
- Verify that 1PL and 2PL are connected.
- Select (**INIT**) from the Test Menu by pressing **1** then **ENTER**.
- Press reset on the DMCB card and you will get **fault 116**.
- Select I/O TEST from the Test Menu by pressing 2 then ENTER.
- Verify **RETURN** and **EXPECTED** on the Computer Screen is equal.
- EE Download
- Select (**Download Core IOS**) from the Test Menu by pressing 6 then **ENTER**
- The following message will appear on Computer Screen.

(Is the Core Model Number a 3VXXXXXX DIXXX Y-N?)

- Answer **Yes** then press **ENTER**.
- The following message will appear on Computer Screen.

(MODEL NO. 3Vxxxxxx DIxxx)

(ENTER DIxxx?)

- Type **DI123** then **ENTER**.
- Answer the following questions that appear about the hardware that are in the unit you are testing.
- After answering the questions about hardware the following message will appear on Computer Screen.

(IS THIS HARDWARE CONFIGURATION OK Y-N?)

- Review the configuration and answer Yes then press ENTER.
- Data will start to scroll across Computer Screen and after download is complete screen will go back to the Main Menu.
- Verify that

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• • 10. <u>SPECIAL INFORMATION</u>	
TEST WRITTEN BY:	DATE:

DATE:

TEST VERIFIED BY: